

Search Notes

Application/Control No.

10/002,554

Examiner

Benny Q. Tieu

Applicant(s)/Patent under
Reexamination

MACARTNEY ET AL.

Art Unit

2614

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Consulted with John Peng (101 issues)	8/21/2006	BQT